

FORM PTO-1449		US Dept. of Commerce Patent and Trademark Office		ATTORNEY DOCKET NO.		SERIAL NO.	
				4173-101		09/884,791	
<b>INFORMATION DISCLOSURE STATEMENT</b> <i>O I P E</i> <small>(use several sheets if necessary)</small> <small>JUL 13 2001</small>		APPLICANT					
		David S. Kurtz, et al.					
		FILING DATE		GROUP		<i>Z621</i>	
		June 19, 2001					
<b>U.S. PATENT DOCUMENTS</b>							
EXAMINER		PATENT NUMBER	ISSUE DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
<i>rim</i>	AA	6,064,717	05/16/00	Ortega, et al.	378	71	
<i>rim</i>	AB	6,005,914	12/21/99	Quinn, et al.	378	81	
<i>rim</i>	AC	5,828,724	10/27/98	Kurtz	378	70	
<i>rim</i>	AD	6,058,160	05/02/00	Kurtz	378	70	
<b>FOREIGN PATENT DOCUMENTS</b>							
		DOCUMENT NUMBER	PUBLICATION DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION YES NO
		<del>0 106 662</del>	<del>4/25/84</del>	<del>Europe</del>			X
<b>OTHER DOCUMENTS (Including Author, Title, Journal-Date, Page Number, Etc.)</b>							
<i>rim</i>	AE	Abstract; Schwarzbau, H.; Equipment Measuring Surface Texture – Uses Monochromatic Radiation to Study Surface Layer of Non-Amorphous Polycrystalline Body; (1980)					
<i>rim</i>	AF	Hans Joachim Bunge and Helmut Klein, Determination of Quantitative, High-resolution Pole Figures with the Area Detector, Z. Metallkd., 87 (1996) pp.465-475					
Continue on Page _____							
EXAMINER	<i>Ryan J. Niles</i>			DATE CONSIDERED <i>6-10-04</i>			
EXAMINER: Initial if citation considered, whether or not citation is in conformance with MPEP § 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to the applicant.							